

F1 THRU F7

1.0 AMP. SURFACE MOUNT GENERAL PURPOSE FAST RECOVERY RECTIFIERS

FEATURES

Glass passivated device

Ideal for surface mouted applications
Low

reverse leakage • Metallurgically bonded

construction

• High temperature soldering guaranteed: 250° C/10 seconds at terminals.

MECHANICAL DATA

- Case: JEDEC SOD-123FL,molded plastic over passivated chip
- Terminals:Solder Plated, solderable per MIL-STD-750, Method 2026

• Polarity: Color band denotes cathode

end • Weight: 0.006 ounces, 0.02 gram

• Mounting position: Any



MAXIMUM RATINGS AND ELECTRONICAL CHARACTERISTICS

Ratings at 25°C ambient temperature unless otherwise specified. Single phase, half wave, 60Hz, resistive or inductive load. For capacitive load, derate current by 20%.

Type Number	SYMBOL	F1	F2	F3	F4	F5	F6	F7	units
	marking								
Maximum Recurrent Peak Reverse Voltage		50	100	200	400	600	800	1000	V
Maximum RMS Voltage	V RMS	35	70	140	280	420	560	700	V
Maximum DC Blocking Voltage	И с	50	100	200	400	600	800	1000	V
Maximum Average Forward rectified	7	1.0							A
Current at $T_A = 65^{\circ}C$ (Note 1)	⊿F(AV)								
Peak Forward Surge Current 8.3ms single									
half sine-wave superimposed on rate load	I FSM		25						A
(JEDEC method)									
Maximum Instantaneous forward Voltage at	14	1.2							
0.7A DC	V F 1.3								v
Maximum DC Reverse Current @T _A =25°C	7	10							μA
at rated DC blocking voltage $@T_A = 125^{\circ}C$	2 R 50.0								
Maximum Reverse Recovery Time (Note 2)	<i>t</i> rr	150			250		500	nS	
Typical Junction Capacitance (Note 3)	G	4							pF
Typical thermal resistance (Note 4)	R (JA)	180							°C /W
Storage Temperature Range	<i>Т</i> ята	-55 to +150							°C
Operation Temperature Range	7 5	-55 to +150							°C

Note: 1. Averaged over any 20 ms period.

2.Test Conditions: I_F =0.5A, I_R =1.0A, I_{RR} =0.25A

3. Measured at 1MHz and applied reverse voltage of 4.0 volts d.c.

4. Measured on P.C.Board with 0.2×0.2"(5.0×5.0mm)Copper Pad Areas



RATING AND CHARACTERISTIC CURVES (F1 THRU F7)



FIG.5-- REVERSE RECOVERY TIME CHARACTERISTIC AND TEST CIRCUIT DIAGRAM

